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		First Named Inventor	Gattiker			
	STATEMENT BY APPLICANT	Art Unit				
	(Use as many sheets as necessary)	Examiner Name				
て	Sheet 1 of 3	Attorney Docket Number	AUS920030653US1			

			U. S. PATENT	DOCUMENTS	
Examiner Initials*	Cite No.1	Document Number Number-Kind Code ^{2 (f Innovn)}	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
:HI		^{US-} 6366108-B1	04-02-2002	Maxwell, et al.	
cdf	-	^{US-} 6175244-B1	01-16-2001	Gattiker, et al.	_
		US-			

FOREIGN PATENT DOCUMENTS								
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		Country Code ³ "Number ⁴ "Kind Code ⁵ (# known)	MM-DD-YYYY		Or Relevant Figures Appear	7		
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		NON PATENT LITERATURE DOCUMENTS	
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uth		KRUSEMAN, ET AL. The Future of IDDQ Testing, IEEE International Test Conference Proceedings, 2001	
CHO		THIBEAULT, Improving Delta-IDDQ-based Test Methods, IEEE International Test Conference Proceedings, 2000	
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CHE		LAVO, ET AL., Eliminating the Ouija Board: Automatic Thresholds and Probabilistic IDDQ Diagnosis, IEEE International Test Conference Proceedings, 1999	
CHO	-	GATTIKER, Current Signatures for Integrated Circuit Test Strategy Advisor, Carnegie Mellon University, Ph.D. Dissertation	
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